



The University of Michigan
Radiation Laboratory
3228 EECS Building
Ann Arbor, MI 48109-2122
Tel: (734) 764-0500
Fax: (734) 647-2106

Measured Radio Frequency Emissions
From

Schrader Electronics Limited Transmitter
FCC ID: MRXSMD3MA4
IC: 2546A-SMD3MA4

Test Report No. 417124-513
June 27, 2009

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For:
Schrader Electronics Limited
11 Technology Park, Belfast Road,
Antrim BT41 1QS, Northern Ireland
Contact: Adrian Condon,
acondon@schrader.co.uk
Phone: +44 (0) 28 9448 3073
Fax: +44 (0) 28 9446 8440

Measurements made by: Valdis V. Liepa

Testing supervised by:
Report Approved by:

Valdis V. Liepa
Research Scientist

Test report written by: Joseph D. Brunett

Summary

Tests for compliance with FCC Regulations, CFR 47, Part 15 and with Industry Canada RSS-210/Gen, were performed on a Schrader, FCC ID: MRXSMD3MA4, IC: 2546A-SMD3MA4. This device under test (DUT) is subject to the rules and regulations as a Transmitter.

In testing completed on June 28, 2009, the DUT tested met the allowed specifications for radiated emissions by 6.0 dB. Conducted emissions are not subject to regulation as the DUT is powered by a 3 VDC battery.

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1. Introduction

This Schrader Transmitter was tested for compliance with FCC Regulations, Part 15, adopted under Docket 87-389, April 18, 1989 as subsequently amended, and with Industry Canada RSS-210/Gen, Issue 7, June 2007. Tests were performed at the University of Michigan Radiation Laboratory Willow Run Test Range following the procedures described in ANSI C63.4-2003 "Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz". The Site description and attenuation characteristics of the Open Site facility are on file with FCC Laboratory, Columbia, Maryland (FCC Reg. No: 91050) and with Industry Canada, Ottawa, ON (File Ref. No: IC 2057A-1).

2. Equipment Used

The test equipment commonly used in our facility is listed in Table 2.1. Except where indicated as a pre-test, monitoring, or support device; all equipment listed below is a part of the University of Michigan Radiation Laboratory (UMRL) quality system. This quality system has been established to ensure all equipment has a clearly identifiable classification, calibration expiry date, and that all calibrations are traceable to national standards.

Table 2.1 Test Equipment.

Test Instrument	Used	Manufacturer/Model	Q Number
Spectrum Analyzer (9kHz-26GHz)	<input checked="" type="checkbox"/>	Hewlett-Packard 8593E, SN: 3412A01131	HP8593E1
Spectrum Analyzer (9kHz-6.5GHz)	<input checked="" type="checkbox"/>	Hewlett-Packard 8595E, SN: 3543A01546	JDB8595E
Power Meter	<input type="checkbox"/>	Hewlett-Packard, 432A	HP432A1
Harmonic Mixer (26-40 GHz)	<input type="checkbox"/>	Hewlett-Packard 11970A, SN: 3003A08327	HP11970A1
Harmonic Mixer (40-60 GHz)	<input type="checkbox"/>	Hewlett-Packard 11970U, SN: 2332A00500	HP11970U1
Harmonic Mixer (75-110 GHz)	<input type="checkbox"/>	Hewlett-Packard 11970W, SN: 2521A00179	HP11970W1
Harmonic Mixer (140-220 GHz)	<input type="checkbox"/>	Pacific Millimeter Prod., GMA, SN: 26	PMPGMA1
S-Band Std. Gain Horn	<input type="checkbox"/>	S/A, Model SGH-2.6	SBAND1
C-Band Std. Gain Horn	<input type="checkbox"/>	University of Michigan, NRL design	CBAND1
XN-Band Std. Gain Horn	<input type="checkbox"/>	University of Michigan, NRL design	XNBAND1
X-Band Std. Gain Horn	<input type="checkbox"/>	S/A, Model 12-8.2	XBAND1
X-band horn (8.2- 12.4 GHz)	<input type="checkbox"/>	Narda 640	XBAND2
X-band horn (8.2- 12.4 GHz)	<input type="checkbox"/>	Scientific Atlanta , 12-8.2, SN: 730	XBAND3
K-band horn (18-26.5 GHz)	<input type="checkbox"/>	FXR, Inc., K638KF	KBAND1
Ka-band horn (26.5-40 GHz)	<input type="checkbox"/>	FXR, Inc., U638A	KABAND1
U-band horn (40-60 GHz)	<input type="checkbox"/>	Custom Microwave, HO19	UBAND1
W-band horn(75-110 GHz)	<input type="checkbox"/>	Custom Microwave, HO10	WBAND1
G-band horn (140-220 GHz)	<input type="checkbox"/>	Custom Microwave, HO5R	GBAND1
Bicone Antenna (30-250 MHz)	<input checked="" type="checkbox"/>	University of Michigan, RLBC-1	LBBIC1
Bicone Antenna (200-1000 MHz)	<input checked="" type="checkbox"/>	University of Michigan, RLBC-2	HBBIC1
Dipole Antenna Set (30-1000 MHz)	<input checked="" type="checkbox"/>	University of Michigan, RLDP-1,-2,-3	UMDIP1
Dipole Antenna Set (30-1000 MHz)	<input type="checkbox"/>	EMCO 3121C, SN: 992 (Ref. Antennas)	EMDIP1
Active Rod Antenna (30 Hz-50 MHz)	<input type="checkbox"/>	EMCO 3301B, SN: 3223	EMROD1
Active Loop Antenna (30 Hz-50 MHz)	<input type="checkbox"/>	EMCO 6502, SN:2855	EMLOOP1
Ridge-horn Antenna (300-5000 MHz)	<input checked="" type="checkbox"/>	University of Michigan	UMRH1
Amplifier (5-1000 MHz)	<input checked="" type="checkbox"/>	Avantek, A11-1, A25-1S	AVAMP1
Amplifier (5-4500 MHz)	<input checked="" type="checkbox"/>	Avantek	AVAMP2
Amplifier (4.5-13 GHz)	<input type="checkbox"/>	Avantek, AFT-12665	AVAMP3
Amplifier (6-16 GHz)	<input type="checkbox"/>	Trek	TRAMP1
Amplifier (16-26 GHz)	<input type="checkbox"/>	Avantek	AVAMP4
LISN Box	<input type="checkbox"/>	University of Michigan	UMLISN1
Signal Generator	<input type="checkbox"/>	Hewlett-Packard 8657B	HPSG1

3. Device Under Test

3.1 Description & Block Diagram

The DUT is a 315 MHz Transmitter designed for automotive/vehicular applications. It is powered by a 3 VDC lithium battery and is housed in a plastic case approximately 6 x 8 x 2.5 cm in dimension. The DUT is potted and permanently affixed in the wheel of a tire. The DUT is designed and manufactured by Schrader Electronics Limited, 11 Technology Park, Belfast Road, Antrim BT41 1QS, Northern Ireland.

Device	[Make], Model	[S/N],P/N	EMC Consideration
DUT	[Schrader], SMD3MA4	[Tx 1]	Normal Operating
DUT	[Schrader], SMD3MA4	[Tx 2]	Repeated Tx
Un-potted	[Schrader], SMD3MA4		for Photos / voltage variation

3.2 Variants & Samples

There is only a single variant of this device. Three samples were provided for testing, one normal sample, one capable of repeated, modulated transmission, and one un-potted for photographs and voltage variation.

3.3 Modes of Operation

The DUT periodically transmits tire pressure data. The device is also capable of being automatically actuated (via LF interrogation) either by in-vehicle LF initiators or by trained personnel during servicing. Per FCC correspondence, service modes fall under FCC part 15.231(a)(5). Figure 6.1 demonstrates compliance with both 15.231(a)(2) and (5). A detailed list of all operating modes is included in the Description of Operation exhibit.

3.4 Exemptions

- The DUT is permanently installed in a transportation vehicle. As such, digital emissions are exempt from regulation (per FCC 15.103(a) and IC correspondence on ICES-003).
- The DUT employs some modes of operation that alert the vehicle user of sudden changes in tire pressure. Such alert modes fall under FCC 15.231(a)(4), and may operate during the pendency of the alarm condition.

3.5 EMC Relevant Modifications

No EMI Relevant Modifications were performed by this test laboratory.

4. Emissions Limits

4.1 Radiated Emissions Limits

The DUT tested falls under the category of an Intentional Radiator. The applicable testing frequencies and corresponding emission limits set by both the FCC and IC are given in Tables 4.1 and 4.2 below.

Table 4.1. TX Emission Limits (FCC: 15.231(e), .205(a); IC: RSS-210 2.7 T5).

Frequency (MHz)	Fundamental Ave. E _{lim} (3m)		Spurious** Ave. E _{lim} (3m)	
	(μV/m)	dB (μV/m)	(μV/m)	dB (μV/m)
260.0-470.0	1500-5000*		150-500	
315.0	2417	67.7	241.7	47.7
433.9	4399	72.9	439.9	52.9
322-335.4 399.9-410 608-614	Restricted Bands		200	46.0
960-1240/1427(IC) 1300-1427 1435-1626.5 1645.5-1646.5 (IC) 1660-1710 1718.9-1722.2 2200-2300	Restricted Bands		500	54.0

* Linear interpolation, formula: $E = -2833.2 + 16.67 * f$ (MHz)

** Measure up to tenth harmonic; 120 kHz BW up to 1 GHz, 1 MHz BW above 1 GHz

Table 4.2. Spurious Emission Limits (FCC: 15.33, .35, .109/209; IC: RSS-210 2.7, T2)

Freq. (MHz)	E _{lim} (3m) μV/m	E _{lim} dB(μV/m)
30-88	100	40.0
88-216	150	43.5
216-960	200	46.0
960-2000	500	54.0

Note: Average readings apply above 1000 MHz (1 MHz BW), Quasi-Peak readings apply to 1000 MHz (120 kHz RBW), PRF of intentional emissions > 20 Hz for QPK to apply.

4.2 Power Line Conducted Emissions Limits

Table 4.3 Emission Limits (FCC:15.107 (CISPR); IC: RSS-Gen, 7.2.2 T2).

Frequency (MHz)	Class A (dBμV)		Class B (dBμV)	
	Quasi-peak	Average	Quasi-peak	Average
.150 - 0.50	79	66	66 - 56*	56 - 46*
0.50 - 5	73	60	56	46
5 - 30	73	60	60	50

Notes:

- The lower limit shall apply at the transition frequency
- The limit decreases linearly with the logarithm of the frequency in the range 0.15-0.50 MHz:
 - *Class B Quasi-peak: $\text{dB}\mu\text{V} = 50.25 - 19.12 * \log(f)$
 - *Class B Average: $\text{dB}\mu\text{V} = 40.25 - 19.12 * \log(f)$
- 9 kHz RBW

5. Measurement Procedures

5.1 Semi-Anechoic Chamber Radiated Emissions

To become familiar with the radiated emission behavior of the DUT, the device is first studied and measured in our shielded semi-anechoic chamber. In the chamber there is a set-up similar to that of an outdoor 3-meter site, with a turntable, an antenna mast, and a ground plane. Instrumentation includes spectrum analyzers and other equipment as needed.

The DUT is laid on the test table as shown in the included block diagram and/or photographs. A shielded loop antenna is employed when studying emissions from 9 kHz to 30 MHz. Above 30 MHz and below 250 MHz a biconical antenna is employed. Above 250 MHz a ridge or standard gain horn antennas are used. The spectrum analyzer resolution and video bandwidths are set so as to measure the DUT emission without decreasing the emission bandwidth (EBW) of the device. Emissions are studied for all orientations (3-axes) of the DUT and all test antenna polarizations. In the chamber, spectrum and modulation characteristics of intentional carriers are recorded. Receiver spurious emissions are measured with an appropriate carrier signal applied. Associated test data is presented in subsequent sections.

5.2 Outdoor Radiated Emissions

After measurements are performed indoors, emissions on our outdoor 3-meter Open Area Test Site (OATS) are made. If the DUT connects to auxiliary equipment and is table or floor standing, the configurations prescribed in ANSI C63.4 are employed. Alternatively, an on-table layout more representative of actual use may be employed if the resulting emissions appear to be worst-case in such a configuration. Any intentionally radiating elements are placed on the test table flat, on their side, and on their end (3-axes) and worst case emissions are recorded. For each configuration the DUT is rotated 360 degrees about its azimuth and the receive antenna is raised and lowered between 1 and 4 meters to maximize radiated emissions from the device. Receiver spurious emissions are measured with an appropriate carrier signal applied. For devices with intentional emissions below 30 MHz, our shielded loop antenna at a 1 meter received height is used. Low frequency field extrapolation to the regulatory limit distance is employed as needed. Emissions between 30 MHz and 1 GHz are measured using tuned dipoles and/or biconical antennas. Care is taken to ensure that the RBW and VBW used meet the regulatory requirements, and that the EBW of the DUT is not reduced. The Photographs included in this report show the DUT on the OATS.

5.3 Radiated Field Computations

To convert the dBm values measured on the spectrum analyzer to dB(μ V/m), we use expression

$$E3(\text{dB}\mu\text{V/m}) = 107 + \text{PR} + \text{KA} - \text{KG} + \text{KE} - \text{CF}$$

where

- PR = power recorded on spectrum analyzer, dB, measured at 3 m
- KA = antenna factor, dB/m
- KG = pre-amplifier gain, including cable loss, dB
- KE = duty correction factor, dB
- CF = distance conversion (employed only if limits are specified at alternate distance), dB

When presenting the data at each frequency, the highest measured emission under all of the possible DUT orientations (3-axes) is given.

5.4 Indoor Power Line Conducted Emissions

When applicable, power line conducted emissions are measured in our semi-anechoic chamber. If the DUT connects to auxiliary equipment and is table or floor standing, the configurations prescribed in ANSI C63.4 are employed. Alternatively, an on-table layout more representative of actual use may be employed if the resulting emissions appear to be worst-case in such a configuration.

The conducted emissions measured with the spectrum analyzer and recorded (in dB μ V) from 0-2 MHz and 2-30 MHz for both the ungrounded (Hi) and grounded (Lo) conductors. The spectrum analyzer is set to peak-hold mode in order to record the highest peak throughout the course of functional operation. Only when the emission exceeds or is near the limit are quasi-peak and average detection used.

5.5 Supply Voltage Variation

Measurements of the variation in the fundamental radiated emission were performed with the supply voltage varied by no less than 85% and 115% of the nominal rated value. For battery operated equipment, tests were performed using a new battery, and worst case emissions are re-checked employing a new battery.

6. Test Results

6.1 Radiated Emissions

6.1.1 Correction for Pulse Operation

When the transmitter is activated (by tire rotation or LF interrogation), it can, in the worst case, transmit one 13.3 ms word every 99.75 ms. Each word contains one 0.525 ms wake pulse, thirteen 0.123 ms timing pulses, another 0.525 ms wake pulse, and thirty-seven 0.123 ms Manchester pulses. See Figure 6.1. Computing the duty factor results in:

$$K_E = (1 \times 0.525 \text{ ms} + 13 \times 0.123 \text{ ms} + 1 \times 0.525 \text{ ms} + 37 \times 0.123 \text{ ms}) / 99.75 \text{ ms} = 0.072 < -20.0 \text{ dB.}$$

6.1.2 Emission Spectrum

The relative DUT emission spectrum is recorded and is shown in Figure 6.2.

6.1.3 Emission Bandwidth

The emission bandwidth of the signal is shown in Figure 6.3. The allowed 99% bandwidth is 0.25% of 315 MHz, or 787.25 kHz. From the plot we see that the EBW is 317.2 kHz, and the center frequency is 315 MHz.

6.1.4 Supply Voltage and Supply Voltage Variation

The DUT has been designed to be powered by a 3 VDC battery. For this test, relative radiated power was measured at the fundamental as the voltage was varied from 2.5 to 4.0 volts. The emission variation is shown in Figure 6.4.

Batteries:	before testing	$V_{oc} = 3.2 \text{ V}$
	after testing	$V_{oc} = 3.0 \text{ V}$
Ave. current from batteries		$I = 0.5 \text{ mA (pulsed)}$

6.2 Conducted Emissions

These tests do not apply, since the DUT is powered from a 3 VDC battery.

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Radiation Laboratory
3228 EECS Building
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Tel: (734) 764-0500
Fax: (734) 647-2106

Table 6.1 Highest Emissions Measured

Radiated Emission - RF											Schrader SUB; FCC/IC
#	Freq. MHz	Ant. Used	Ant. Pol.	Pr dBm	Det. Used	Ka dB/m	Kg dB	E3* dBµV/m	E3lim dBµV/m	Pass dB	Comments
1	315.0	Dip	H	-23.2	Pk	18.6	20.7	61.6	67.7	6.0	flat
2	315.0	Dip	V	-29.1	Pk	18.6	20.7	55.7	67.7	11.9	end
3	630.0	Dip	H	-62.0	Pk	24.4	17.7	31.7	47.7	16.0	flat
4	630.0	Dip	V	-61.3	Pk	24.4	17.7	32.4	47.7	15.3	end
5	945.0	Dip	H	-63.0	Pk	28.8	15.7	37.2	47.7	10.5	side
6	945.0	Dip	V	-63.9	Pk	28.8	15.7	36.3	47.7	11.4	end
7	1260.0	Horn	H	-45.7	Pk	20.6	28.1	33.8	54.0	20.2	side
8	1575.0	Horn	H	-52.1	Pk	21.5	28.1	28.3	54.0	25.7	flat
9	1890.0	Horn	H	-59.6	Pk	22.2	28.1	21.5	54.0	32.5	flat
10	2205.0	Horn	H	-68.4	Pk	23.0	26.5	15.1	54.0	38.8	end
11	2520.0	Horn	H	-66.7	Pk	23.9	26.0	18.2	54.0	35.8	side
12	2835.0	Horn	H	-72.5	Pk	24.8	24.7	14.6	54.0	39.4	flat, noise
13	3150.0	Horn	H	-72.2	Pk	25.8	23.6	17.0	54.0	36.9	flat, noise
14											
15											
16											
17											
18	* Includes 20 dB duty factor										
19											
20											
21											
22											
23											
24											
25											
26											
27											
Digital Radiated Emissions*											
#	Freq. kHz	Ant. Used	Ant. Pol.	Pr dBm	Det. Used	Ka dB/m	Kg dB	E3 dBµV/m	E3lim dBµV/m	Pass dB	Comments
1											
2											
3											
4	Digital emissions more than 20 dB below FCC/IC Class B Limit.										
5											
6											
7											
8											
9	* For devices used in transportation vehicles, digital emissions are exempt from FCC regulations per FCC 15.103(a)										

Meas. 06/18/2009; U of Mich.

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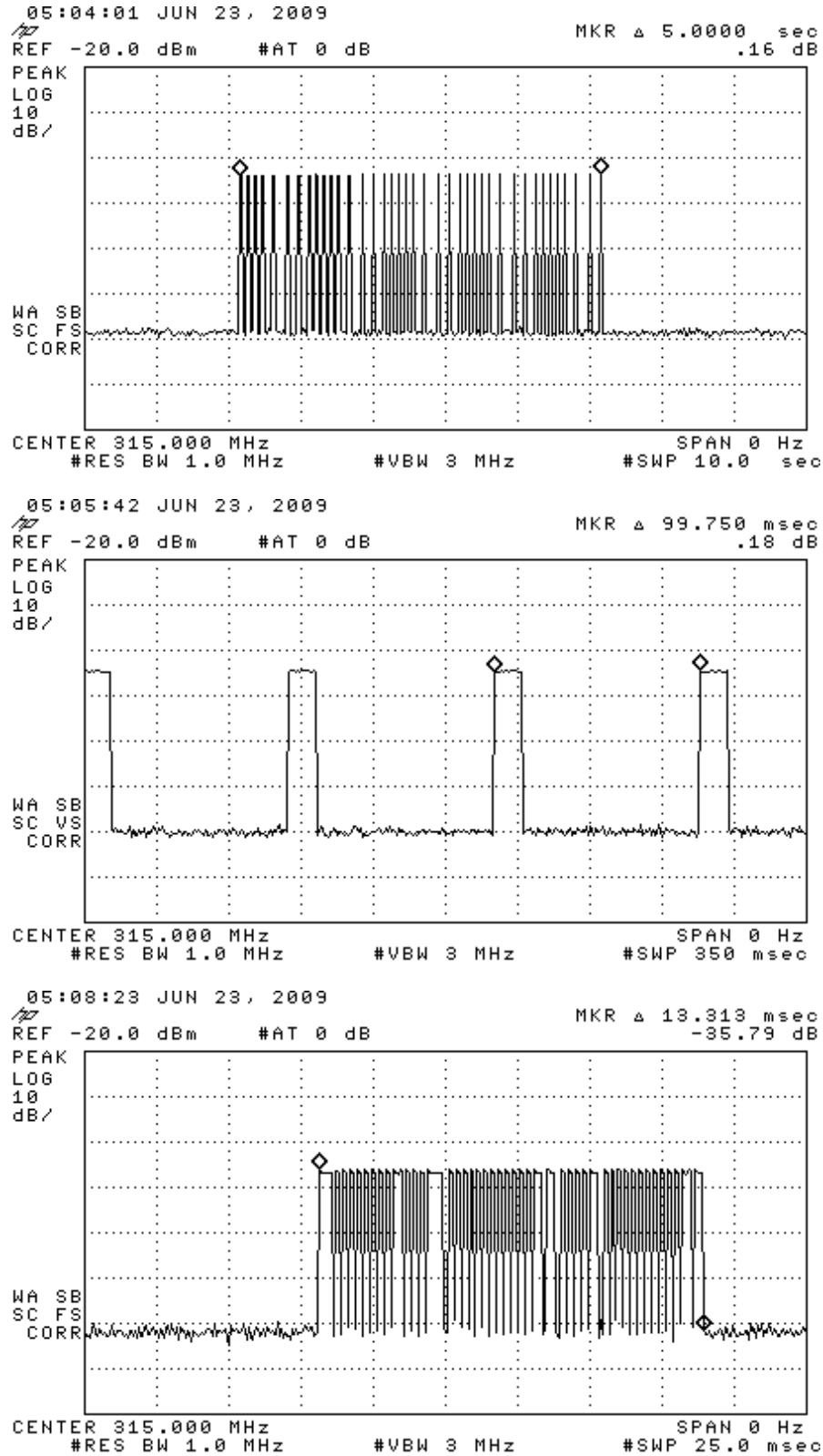


Figure 6.1(a). Transmission modulation characteristics. (top) LF response transmission, (center) expanded worst case word repetition rate, (bottom) expanded word showing Wake + Manchester encoding.

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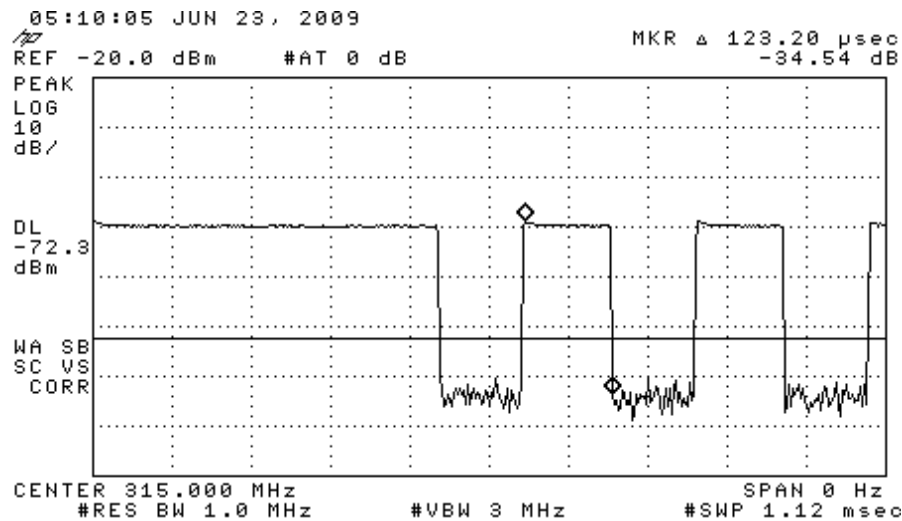
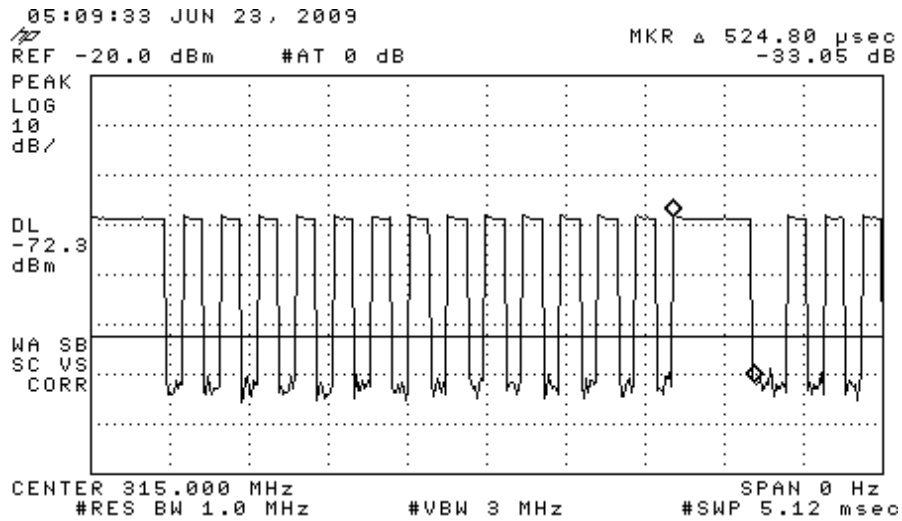
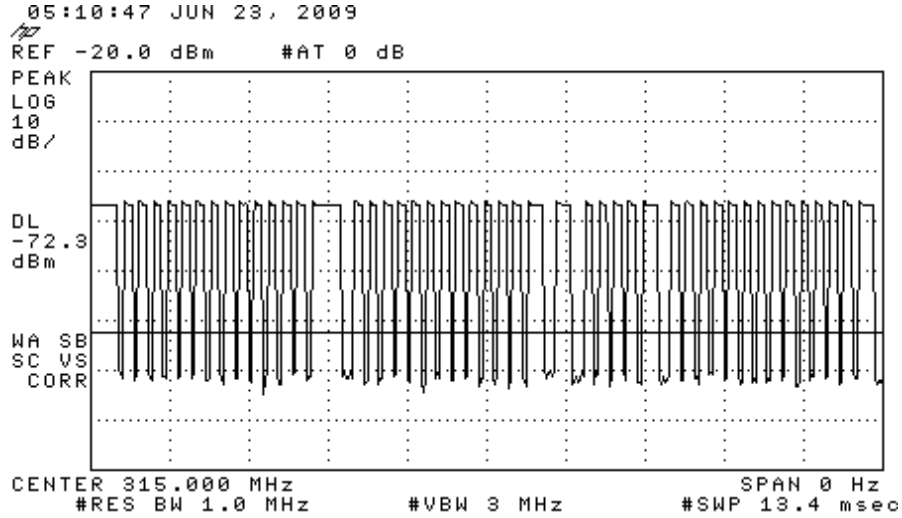


Figure 6.1(b). Transmission modulation characteristics. (top) Wake + Manchester, (center) Wake pulse width, (bottom) Manchester pulse width.

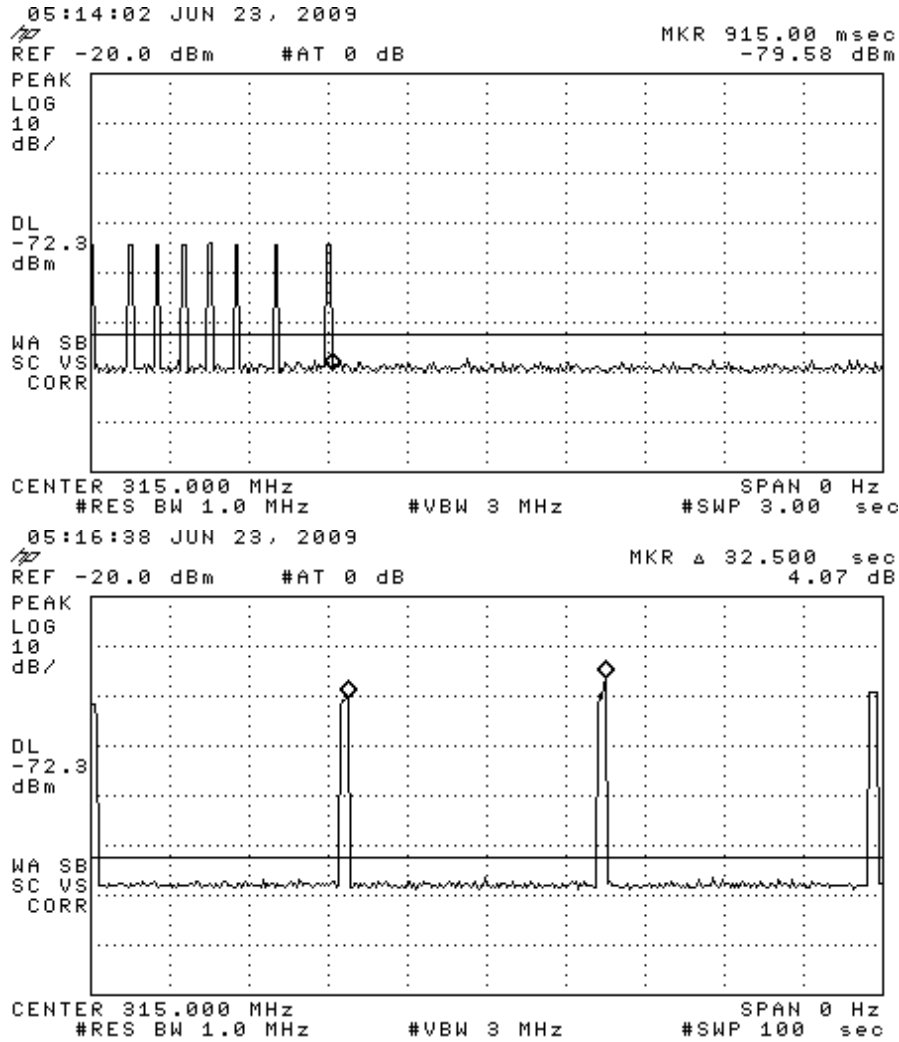


Figure 6.1(c). Transmission modulation characteristics. (top) Drive mode transmission – 8 words identical to LF induced, (bottom) (Factory) Drive mode period (amplitude varies as DUT is shaken to actuate)

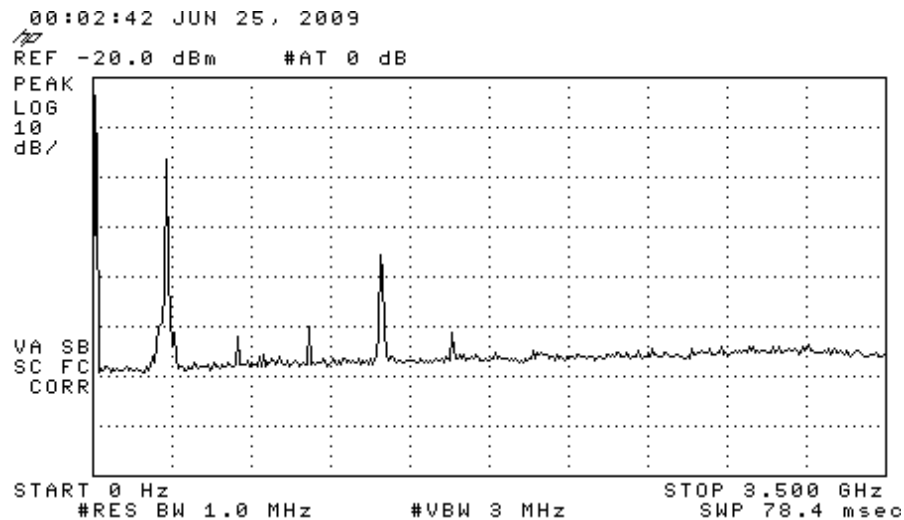


Figure 6.2. Emission spectrum of the DUT (pulsed emission). Amplitudes are only indicative (not calibrated).

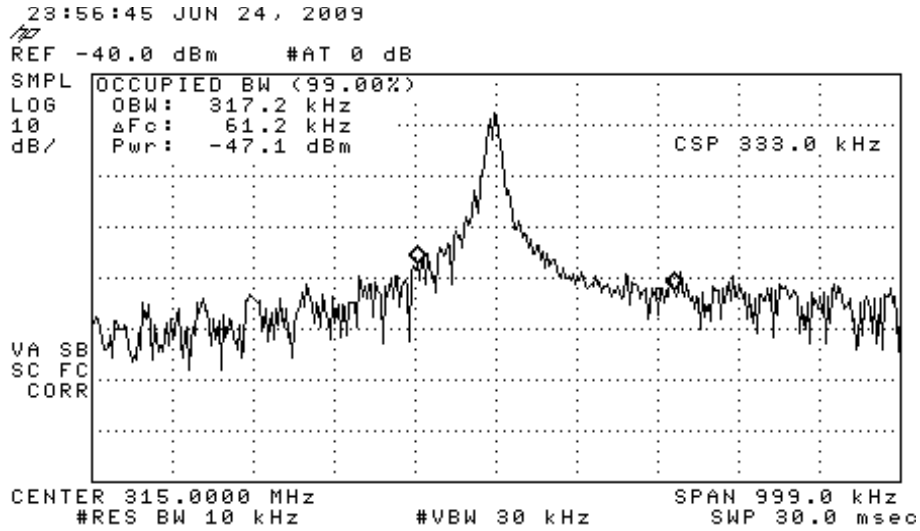


Figure 6.3. Measured emission bandwidth of the DUT (pulsed).

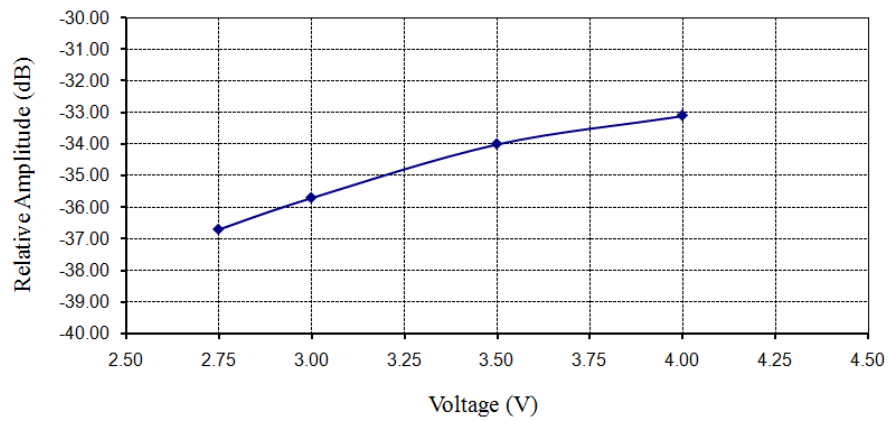
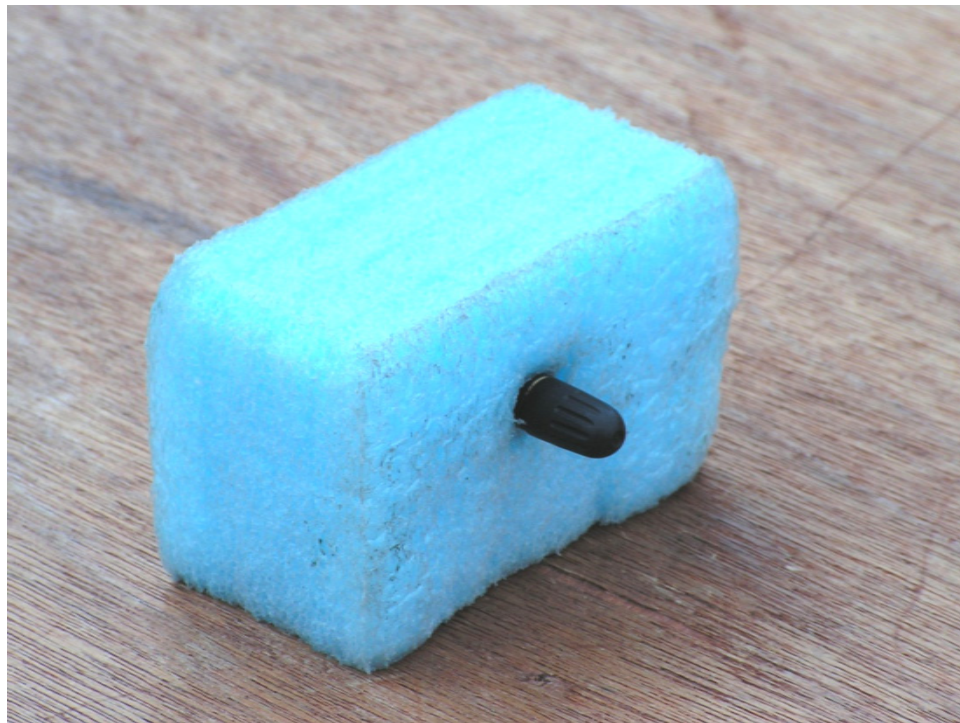


Figure 6.4. Relative emission at fundamental vs. supply voltage (pulsed).



Photograph 6.5. DUT on OATS (one of three axes tested)



Photograph 6.6. Close-up of DUT on OATS (one of three axes tested)